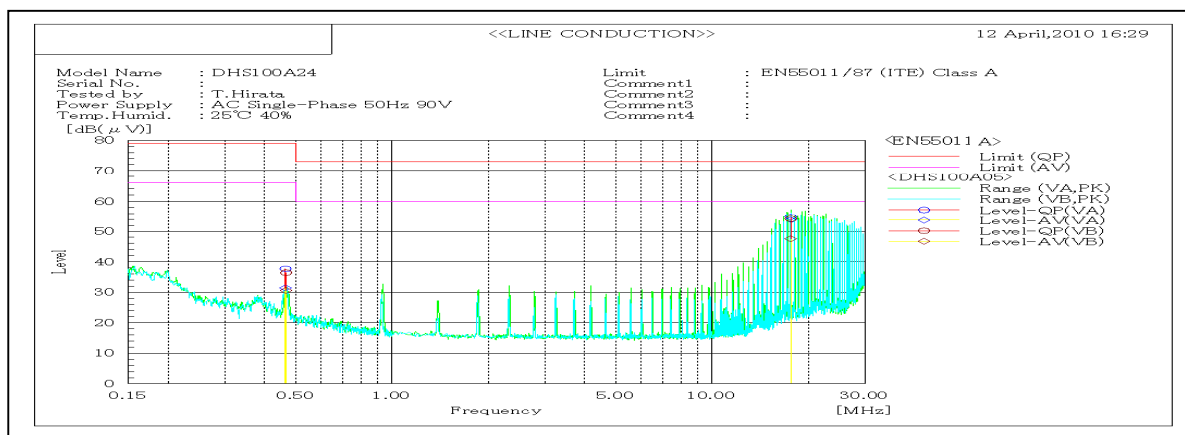
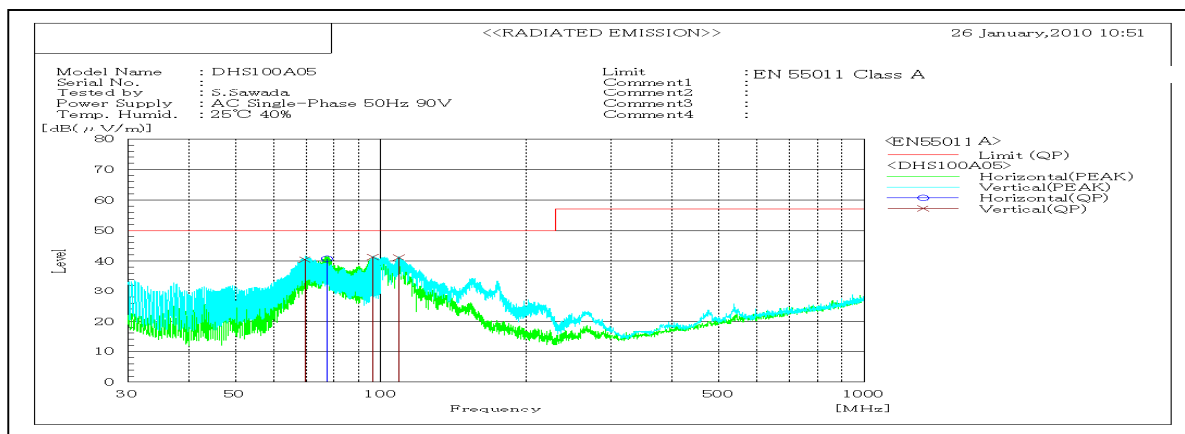


DATA SHEET		Date	26-Apr-10
Model	DHS100A05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Hirata



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46683		VB	26.4	20.6	10	36.4	30.6	79	66	42.6	35.4	Pass	
0.46476		VA	27.6	21.3	10.1	37.7	31.4	79	66	41.3	34.6	Pass	
17.6196		VB	43.2	36.5	11	54.2	47.5	73	60	18.8	12.5	Pass	
17.6142		VA	44	43	10.8	54.8	53.8	73	60	18.2	6.2	Pass	



Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB(μV)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
69.616		V		Stable	65.9			-25.4	40.5			50			9.5			Pass	109	63	
77.373		H		Stable	65.5			-24.8	40.7			50			9.3			Pass	157	160	
96.249		V		Stable	63.7			-22.3	41.4			50			8.6			Pass	152	269	
108.818		V		Stable	61.6			-20.4	41.2			50			8.8			Pass	142	314	

# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission

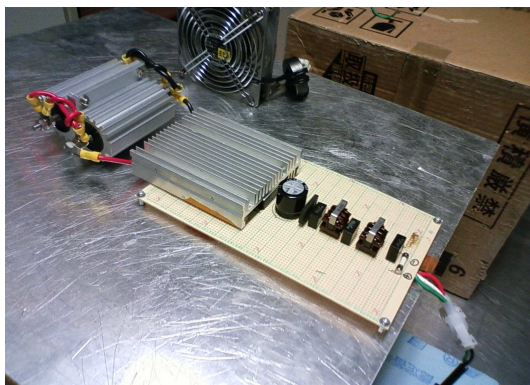


Test: EMI

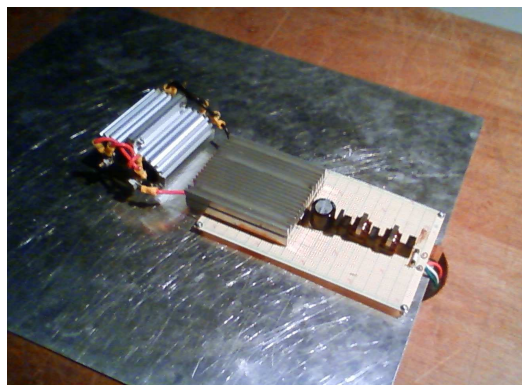
Model Name:DHS50A/DHS100A Series

## ○ Photographs of Test Set-Up

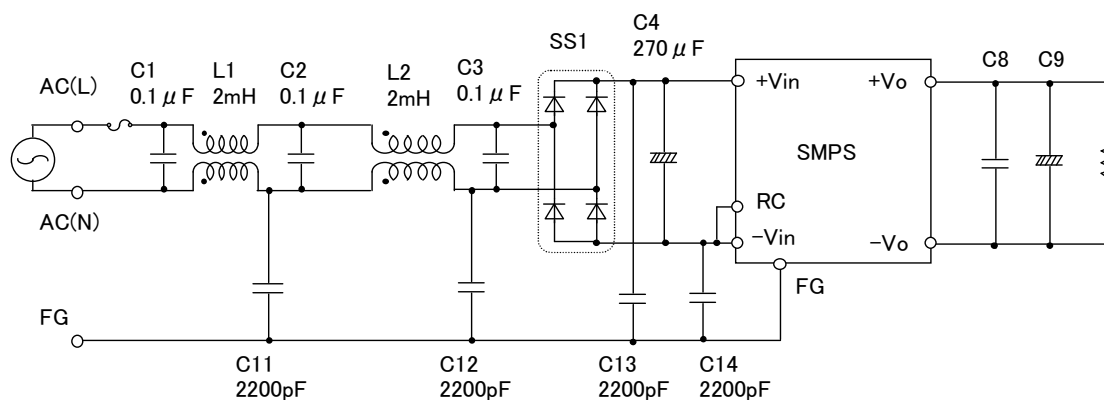
### LINE CONDUCTION



### RADIATED EMISSION



## ○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
		Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
		DHS50A12/DHS100A12 470 μ F
		DHS50A15/DHS100A15 470 μ F
		DHS50A24/DHS100A24 220 μ F